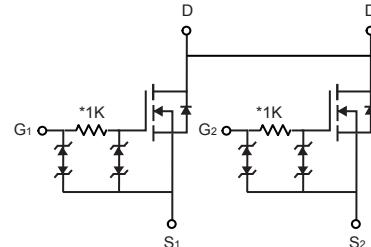


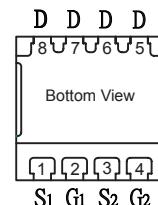
Dual N-Channel Enhancement Mode Field Effect Transistor

FEATURES

- 20V, 6.5A, $R_{DS(ON)} = 23m\Omega$ @ $V_{GS} = 4.5V$.
 $R_{DS(ON)} = 34m\Omega$ @ $V_{GS} = 2.5V$.
- Super High dense cell design for extremely low $R_{DS(ON)}$.
- High power and current handing capability.
- Lead free product is acquired.



DFN3*3



ABSOLUTE MAXIMUM RATINGS

$T_A = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	V_{DS}	20	V
Gate-Source Voltage	V_{GS}	± 12	V
Drain Current-Continuous	I_D	6.5	A
Drain Current-Pulsed ^a	I_{DM}	25	A
Maximum Power Dissipation	P_D	1.5	W
Operating and Store Temperature Range	T_J, T_{Stg}	-55 to 150	$^\circ C$

Thermal Characteristics

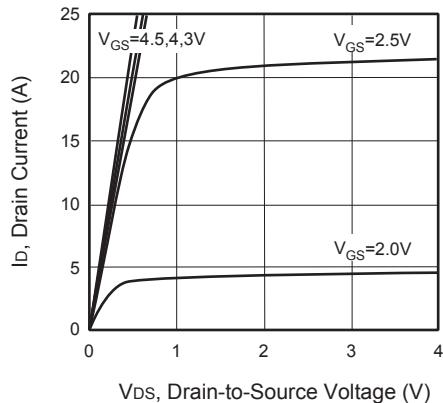
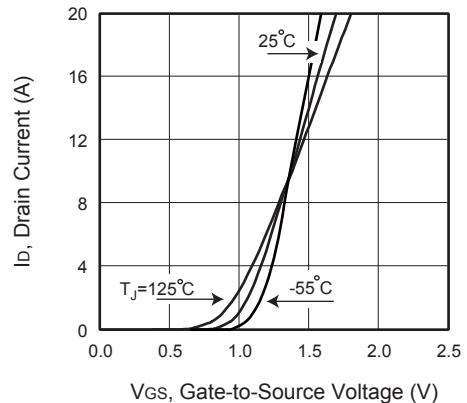
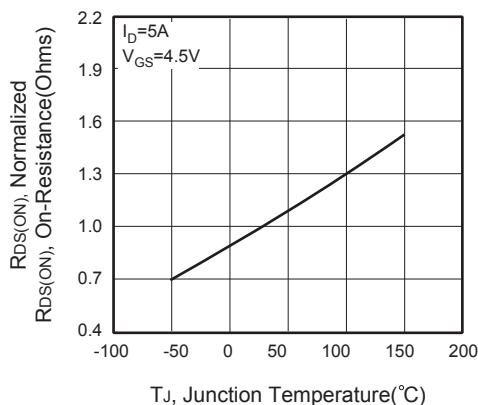
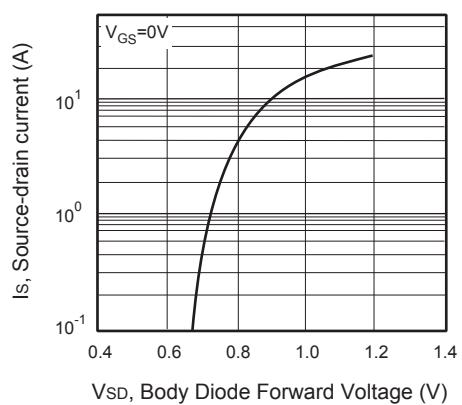
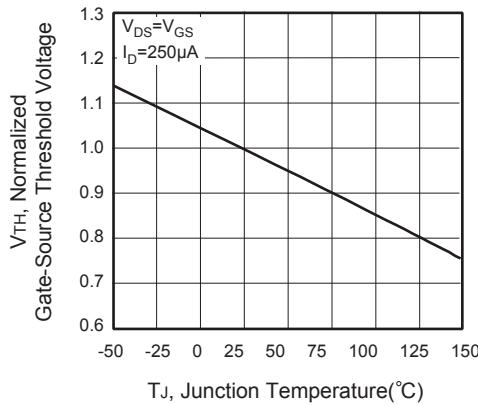
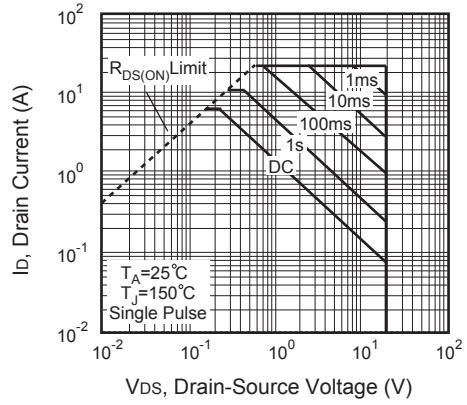
Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Ambient ^b	$R_{\theta JA}$	83	$^\circ C/W$



CEC8218

Electrical Characteristics $T_A = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	20			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}$		1		μA
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{\text{GS}} = 12\text{V}, V_{\text{DS}} = 0\text{V}$		10		μA
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{\text{GS}} = -12\text{V}, V_{\text{DS}} = 0\text{V}$		-10		μA
On Characteristics ^c						
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = 250\mu\text{A}$	0.5		1.2	V
Static Drain-Source	$R_{\text{DS(on)}}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 5\text{A}$		17	23	$\text{m}\Omega$
On-Resistance		$V_{\text{GS}} = 2.5\text{V}, I_D = 4\text{A}$		24	34	$\text{m}\Omega$
Dynamic Characteristics ^d						
Forward Transconductance	g_{FS}	$V_{\text{DS}} = 10\text{V}, I_D = 5\text{A}$		17		S
Switching Characteristics ^d						
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}} = 10\text{V}, I_D = 1\text{A}, \square$ $V_{\text{GS}} = 4.5\text{V}, R_{\text{GEN}} = 6\Omega$		0.34	0.68	μs
Turn-On Rise Time	t_r			0.86	1.72	μs
Turn-Off Delay Time	$t_{\text{d(off)}}$			3.60	7.5	μs
Turn-Off Fall Time	t_f			2	4	μs
Total Gate Charge	Q_g	$V_{\text{DS}} = 10\text{V}, I_D = 5\text{A}, \square$ $V_{\text{GS}} = 4.5\text{V}$		4.2	5.6	nC
Gate-Source Charge	Q_{gs}			1.2		nC
Gate-Drain Charge	Q_{gd}			2.5		nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Current ^b	I_S				6.5	A
Drain-Source Diode Forward Voltage ^c	V_{SD}	$V_{\text{GS}} = 0\text{V}, I_S = 1.5\text{A}$			1.2	V
Notes : a.Repetitive Rating : Pulse width limited by maximum junction temperature. b.Surface Mounted on FR4 Board, $t \leq 10$ sec. c.Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$. d.Guaranteed by design, not subject to production testing. □						

**Figure 1. Output Characteristics****Figure 2. Transfer Characteristics****Figure 3. On-Resistance Variation with Temperature****Figure 4. Body Diode Forward Voltage Variation with Source Current****Figure 5. Gate Threshold Variation with Temperature****Figure 6. Maximum Safe Operating Area**

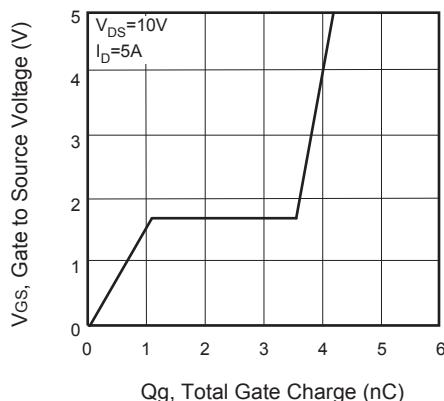


Figure 7. Gate Charge

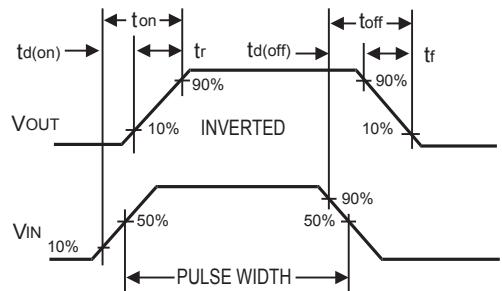


Figure 8. Switching Waveforms



Figure 9. Switching Test Circuit

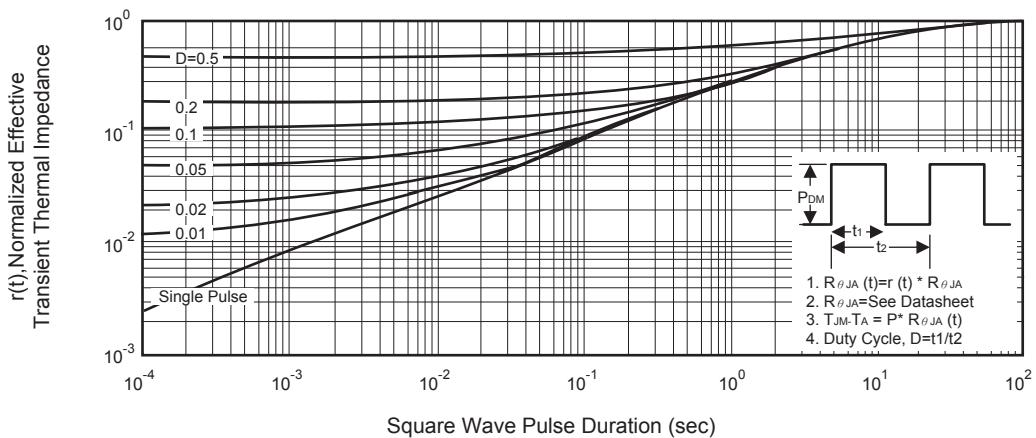


Figure 10. Normalized Thermal Transient Impedance Curve